

### IFE Materials Response: Long-term exposure to nitrogen and helium beams on RHEPP

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 Sample temperature held to 580 < T < 600C - above brittle-ductile transition temp for both Mo and W

- Roughening threshold for pure W appears to be ~ 1.25 J/cm<sup>2</sup>, same as previously measured at RT by reflectometer. Similar scaling with fluence for W25Re
- Mo exposed at 1.5 2.5 J/ cm<sup>2</sup> roughens worse than heated W
- Both W and Mo appear to roughen below melt

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Mo explored at 1.5 - 2.5 J/ cm<sup>2</sup> roughens worse than pated W

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### **Executive Summary**



- Materials response to pulsed ion exposure is affected greatly by grain structure. Roughening appears species-dependent for same dose, He ions roughen worse than N.
- Roughening: is worst for PowderMet W, heated or not. Response varies significantly amongst metals tested, Cu roughens hardly at all, for example. Roughening evolves over hundreds of pulses, and appears open-ended. Smaller-grain PowderMet W might help.
- Deep-lying cracking evident with W, W25Re, and Re. Depths are in the tens to hundreds of microns, and appear consistent with fatigue/stress cracking. Too deep for DekTak/WYCO to see.
- CFC Graphite (222-FMI) suffers material loss over 1000 pulses at the 1.6 J/cm<sup>2</sup> level, well below predicted ablation threshold.
- Foams seem to suffer material loss over 800 pulses, but hard to tell exactly.
- C-C-W Velvet (Knowles) subjected to 200 pulses up to 7 J/cm<sup>2</sup>, survives amazingly well.
- Copper contamination an issue, but does not change major conclusions





#### Extended shot series taken since June 2003





450x Helium Series: W, Mo Powder Met CVD SingXtal, all 600C W25Re, Re unheated	W W
1000x Nitrogen KS Series: Mo Powder Met 600C W25Re, Re Foams Al1100, Cu	W, CFC, Ti-2,
600x Nitrogen series: W, Mo Powder Met 600 C CFC, Foams higher fluence	
	450x Helium Series: W, Mo Powder Met CVD SingXtal, all 600C W25Re, Re unheated 1000x Nitrogen KS Series: Mo Powder Met 600C W25Re, Re Foams Al1100, Cu 600x Nitrogen series: W, Mo Powder Met 600 C CFC, Foams higher fluence



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#### Nitrogen injection into MAP produces 3-component beam of mostly N++, N+





- Beam predominantly N++ and N+ after small proton pulse at front
- Peak voltage = 850 kV
  Peak current density (total) ~145 A/cm<sup>2</sup>
- Total fluence = 7.9 J/cm<sup>2</sup> will ablate almost all materials
- Total pulse width ~ 200 ns
- Ion range (TRIM):
  - N+ 0.9 μm, N++ 1.2 μm
- Oxygen, Neon beams similar





### He beam (HE<sup>+1</sup>) pulsewidth is longer than N or C beam





 He current lags voltage, leading to debunching

- Current pulse width at 63 cm is almost 0.5 µsec long
- Beam here was intentionally attentuated
- He range in W (TRIM) ~ 0.9 μm

• Range similar to N beam because singly charged







## Roughening of SS303, SS316LS varies with ion beam species





- Polished SS303, 316LS exposed to 25 pulses each of 3 beams at 2 J/cm<sup>2</sup>: proton nitrogen argon
- Proton beam produces most roughening (R<sub>a</sub> and peakvalley)
- 303 roughens more in all cases then 316LS
- MAP N and MAP Ar produce similar roughening, Ar smaller peak-valley





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#### Surface morphology changes on SS samples depend upon treatment ion(s)



**Map P 25x** 



Modeling (Fe): Max Temp: 1658K No melting



Modeling (Fe): Max Temp: 2593K Melt depth: 0.7 µm Modeling (Fe):

Max Temp: 2072K Melt Depth: 0.45 µm

- SS303 exposed to 25 shots each Map P, Map N, Map Ar @  $2^{J}/cm^{2}$
- 'Finer' surface features with N, Ar
- Periodicity ~ 50 μm for N, Ar surface, ~ 70 μm for proton-treated surface

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Map Ar 25x



#### RHEPP-1 on Ti Alloy with 160-pulses O beam: Materials response governed at grain level





- ~2.0 J/cm<sup>2</sup> R<sub>a</sub> ~ 0.15 μm Ablation: Minimal Melt depth: 1.5 μm
- ~2.3 J/cm<sup>2</sup> R<sub>a</sub> ~ 0.25 µm Ablation: ~25 Å/pulse Melt depth: 1.75 µm
- ~2.7 J/cm<sup>2</sup> R<sub>a</sub> ~ 1 µm Ablation: ~300 Å/pulse Melt depth: ~2.25 µm
- 600-800 kV, up to 200 A/cm<sup>2</sup> (center-peaked)
- Cratering, roughening worst at intermediate dose
- ~4.0 J/cm<sup>2</sup> R<sub>a</sub> ~ 2 μm Ablation: ~2000 Å/pulse Melt depth: 3.25 μm
- ~6.0 J/cm<sup>2</sup> R<sub>a</sub> ~ 0.6 μm Ablation: >3000 Å/pulse Melt depth: > 4 μm

5X microscope images Grains ~ 1 - 3 mm

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1000 shot KS Series: Test heated W, Mo at low level, Materials Tests of W25Re, Re, Cu, Ti-2, Al1100, Foams, CFC





- Photo shows plate with heated W, Mo on right. Goal: melting temp (max 2.5 J/cm<sup>2</sup>)
- Other (unheated) samples arrayed on left. CFC and Foams at 1.6 J/  $cm^2,\,rest$  up to  $\,$  4 J/  $cm^2$
- Samples shot 200X, Ra measured by 1-D Dektak, then reloaded for another 200X (not Foams and CFC)
- SEMS, WYCO 2-D profilometry after 1000X (800X for foams and Cu)
- W/Mo + Foams and CFC exposed at higher dose on next 600 shot series
- Foams: W, Re, Nb, Mo



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#### Tungsten roughening (Room Temperature): Detailed History of Reflectometer measurements





- Polished W exposed to N beam: 0.6
  <dose< 1.25 J/cm<sup>2</sup> (53 shots)
- Reflectometer photodiode signal (red)
  plotted as function of shot number (26081
   26127)
- Initial exposure at 1 J/cm<sup>2</sup> or less:
  photodiode remains above 20 mV
- Note progressive signal decrease aftershot 26,112.Fluence is ~1.25 J/cm²





#### 400 shot Map N shots on Tungsten (Room Temperature): Roughening only above threshold





- Polished W exposed to 400 shots N beam: 1.0 < fluence < 3.7 J/cm<sup>2</sup>
- Room Temp (RT) exposure
- Roughening occurs above 1.25 J/cm<sup>2</sup>, consistent with single-shot reflectometer roughening threshold
- Powder Met Mo (one point at 2.5 J/cm<sup>2</sup>): roughness stays near unexposed value
- Above threshold, roughening is a severe function of fluence. Maximum R<sub>a</sub> exceeds 22 µm, with P-V height above 70 µm





#### He Beam exposure, 450 shots; Powder Met W has worst roughening, even when heated





- Smoothed PowderMetW, CVDW, and single XtalW, provided by Lance Snead, were exposed to 450 MAP He pulses ~ 1.0 to 1.3 J/cm<sup>2</sup>. Heated to 600C, heated 3X including heater failure
- W/25Re and Re samples also treated, from 1.3 to 2.5 J/cm<sup>2</sup>. Samples at RT
- PwderMetW Roughening is significantly worse than CVD or Single Crystal W. Latter are similar to powderMet W/25Re and Re. None are roughening appreciably compared to untreated.
- Surface morphology for SingXtal and CVD W different from PowderMetW.

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#### He Beam treatment 450 shots: 600C W roughens w/o melt worse than W/Re with melt





Single Xtal W (Snead) Fluence: 1 - 1.3 J/ cm<sup>2</sup> Max Temp (Code): 1900K R<sub>a</sub>: 0.5 - 0.6 µm

Powder Met W Same fluence R<sub>a</sub>: 2 - 3 μm

These surfaces did not melt



W/25Re Fluence: up to 4 J/ cm<sup>2</sup>  $R_a$  : < 0.2  $\mu$ m (Circles are melted Cu)

This surface melted

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#### Evolution of R<sub>a</sub> Roughness for W: PowderMet, CVD, SingXtal - He and N beams, up to 1000 shots



- Polished W samples exposed to 450 shots He, and 600/1000 shots N beam: 1.25 (He) < fluence < 2.5-4.5 J/cm<sup>2</sup> (N)
- All samples exposed at 550-600C
- PowderMet W roughens much worse than CVD or SingXtal (one data pt)
- Roughening with shot number up to 600-100 shots for PowderMet. Slope for 4.5 J/ cm<sup>2</sup> twice that of 2.5 J/cm<sup>2</sup>
- Roughening with He beam at 1.25 J/cm<sup>2</sup> comparable to N at 2.5 J/cm<sup>2</sup>
- Peak-Valley plot almost identical with R<sub>a</sub> plot, except max = 80 μm





Evolution of R<sub>a</sub>, Peak-Valley Roughness at 2.5 J/cm<sup>2</sup>: WPowderMet is worst, then Al1100, Mo and Ti-2





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#### Evolution of R<sub>a</sub> Roughness at 4.0 J/cm<sup>2</sup>: WPowderMet, then everything else. Cu does NOT roughen





- 4 J/cm<sup>2</sup> is near or above ablation level for most metals shown
- Polished W and Mo are heated to 550 600C
- W roughens beyond 10  $\mu m\,R_a$  at 400-600 shots (only 600 taken)
- + W25Re, Re reach 2  $\mu m\,R_a$  at 1000 shots, but Cu remains below 1  $\mu m$
- Ti-2 (not shown) roughens steadily to 1000 shots
- W Peak-Valley exceeds 70 µm at 600 shots



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I-D 8 mm Profilometer Scans, 450x He (Left) and Nitrogen (Right)



P-V ~ 10-30 μm

P-V ~ 5-15 μm

Ra ~ 4-9 µm P-V ~ 20-35 µm

Ra ~ 7-10 µm P-V ~ 50-70 μm



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W (Powder Met) roughening: SEM images as function of shot number: 60 to 1000X





(N 60X @ 6 J/cm<sup>2</sup>)

(N 250X @ 2.5 J/cm<sup>2</sup>)

He 450X @ 1-1.3 J/cm<sup>2</sup>)



(N 600X @ 4.0 J/cm<sup>2</sup>)



(N 1000X @ 2.5 J/cm<sup>2</sup>)



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SEM images of different metals @ 500X Mag: 450XHe to 1000X N





Ti-2 1000X @ 2.6 J/cm<sup>2</sup>)



(Cu 1000X @ 2.6 J/cm<sup>2</sup>)



(Re 1000X @ 2.6 J/cm<sup>2</sup>)







#### SEM images of Ti-2 and Re: Lateral scale length with fluence increase



(Re 1000X @ 2.6 J/cm<sup>2</sup>)

Length scale decreases for Ti-2, increases for Re





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#### (Upper) SEM : Al1100, 1000x Map N @ 500X Mag Lower: Cu 1000x Map N @ 2.5 J/cm<sup>2</sup>





Al1100 1000xN @ 0.85 J/cm<sup>2</sup>



Al1100 1000xN @ 1.6 J/cm<sup>2</sup>



Al1100 1000xN @ 2.5 J/cm<sup>2</sup> Y Profile





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#### W and Mo Foam SEM images as function of fluence





W Untreated



W Treated at 1.6 J/cm<sup>2</sup> 600 shots



W Treated at 3.0 J/cm<sup>2</sup> 600shots







Mo Treated at 3.0 J/cm<sup>2</sup> 600 shots



Mo Untreated

All images 50X magnification



#### Re and Nb Foam SEM images as function of fluence





**Re Untreated** 



Re Treated at 1.6 J/cm<sup>2</sup> 600 shots



W Treated at 3.0 J/cm<sup>2</sup> 600 shots







Nb Treated at 3.0 J/cm<sup>2</sup> 600 shots



Nb Untreated

All images 50x magnification

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### Response of graphite to mixed H - C beam qualitatively confirms BUCKY predictions





- Mechanically polished pyrolitic graphite (PG), Poco, and 4D carbon composite weave exposed to 75 pulses/225 pulses of 70% C /30% H beam at doses of 1.9 to 5 J/cm<sup>2</sup>
- PG ablation threshold ~ 4 J/cm2
- Poco ablation threshold ~ 3 J/cm2
- Above threshold, rapid increase in ablated material per pulse with dose. Data scatter reflects uncertainty in dose
- Composite matrix ablates more than PG/Poco, fibers comparable (sample rough)





### FMI-222 unheated CFC exposed to MAP N for 1000X at 1.6 J/cm<sup>2</sup>: Significant erosion of matrix









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#### FMI-222 Fiber ends appear ablation-resistant; Matrix loss ~ 0.3 µm/pulse at 4.0 J/cm<sup>2</sup>:





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#### FMI-222 CFC SEM images as function of fluence





Treated at 1.6 J/cm<sup>2</sup> 1000X 120MAG

Treated at 2.6 J/cm<sup>2</sup> 600X 120MAG





Fiber end 4.0 J/cm<sup>2</sup> 600X Bottom images all 500MAG



Matrix 4.0 J/cm<sup>2</sup> 600X



Untreated fiber end

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## ESLI CCV/W Test Specimen

ESLI Carbon-Carbon Velvet (CCV) with sputtered-W Coating Carbon fiber volume packing 1.9% Sputtered-W film thickness 1.6 μm over area Thick (1.6 μm) caps on fiber tips; thin (<0.1 μm) film on fiber shafts (thickest at top) Design for RHEEP incidence angle (0.3-0.5 radian) Fluence distribution On flat fiber tops 100% of incident fluence

On flat fiber tops On fiber shafts On graphite substrate 100% of incident fluence< 25% of incident fluence (max near top)</li><5% of incident fluence</li>



# **RHEPP** Exposure

- Specimen was exposed to 200 shots on RHEPP Exposed at SNL, August 2003
- A Ta mask covered a portion of the specimen
  - The exposed portion appears blacker, cleaner than the masked portion
  - Horizontal fibers are eroded entirely
- Fluence gradient along 50-mm strip of specimen
  - High fluence end  $\sim 6-7 \text{ J/cm}^2$ 
    - Expect to ablate solid W at this fluence
    - Low fluence end  $$\sim 1 \ J/cm^2$$

Expect 1500 K max T on solid W at this fluence

ESLI

# CCV/W at Low Exposure (Side)



ESLI Materials and Processing

HAPL Sep 2003 (Madision, WI)

## CCV/W at Medium Exposure









### Summary



- Tungsten: surface roughening excessive (PowderMet), with fatigue cracking below surface maybe even worse. Mitigating: CVD/SingXtal, alloying with Re, heating. Cracking looks like enough to compromise performance as armor coating.
- Roughening occurs over hundreds of shots. Topology may stabilize for W by 1000 shots, looks to increase for other metals beyond this.
- Below the roughening threshold (1.25 J/cm<sup>2</sup>), W may be topologically stable to repeated ion exposure.
- If there is a material loss threshold for CFC Graphite (222-FMI), it is below the 1.6 J/cm<sup>2</sup> level.
- Performance of foams needs further study.
- Most promising performers? C-C-W Velvet, foam possibly. Most 'unroughened': Cu



### Conclusions

- CCV/W can be fabricated with controlled packing density, fiber orientation, W film coating suitable for RHEPP exposure
- Low fluence response shows damage to coating
  - W films peel off fibers, accumulate at base
- High fluence response shows much less damage
  - No apparent damage to substrate velvet protects substrate from RHEPP exposure
  - No W debris accumulating at substrate
  - Fiber shafts are slightly roughened (<1  $\mu$ m)
  - Fiber tips show some erosion
- High fluence heating appears to join W to C